

<b>Notice of References Cited</b>	Application/Control No. 10/553,299		Applicant(s)/Patent Under Reexamination BUECHNER, DETLEF ALFONS	
	Examiner DAVID H. BANH		Art Unit 4193	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,278,921 A	07-1981	Medding et al.	318/254
*	B	US-4,368,394 A	01-1983	Naimer, Hubert L.	307/115
*	C	US-4,886,680 A	12-1989	Tindall, John D.	427/8
*	D	US-5,200,648 A	04-1993	Vyas, Hari J.	327/184
*	E	US-5,278,489 A	01-1994	Bowers, Mark C.	323/225
*	F	US-5,300,096 A	04-1994	Hall et al.	607/48
*	G	US-5,455,764 A	10-1995	Meihofer, Edward	700/41
*	H	US-5,740,211 A	04-1998	Bedrosian, Paul Stephan	375/371
*	I	US-6,284,167 B1	09-2001	Fujikawa, Misao	264/39
*	J	US-6,343,549 B1	02-2002	Tokiwa, Shizurou	101/248
*	K	US-2002/0171581 A1	11-2002	SHEYNBLAT et al.	342/357.09
*	L	US-6,724,840 B1	04-2004	Osofsky et al.	375/346
*	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
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	X				

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